Issue Classification

App	lication	/Contro	l No
-----	----------	---------	------

10020240

Examiner

Nguyen, My X

Applicant(s)/Patent Under Reexamination

TANAKA ET AL.

Art Unit

2617

ORIGINAL					INTERNATIONAL CLASSIFICATION											
CLASS S			SUBCLASS		CLAIMED				LAIMED	NON-CLAIMED						
455 414.1					н	0	4	М	3 / 42 (20	06.0)		\perp				
:	CR	OSS REF	ERENCE(S)								-	+	-		
CLASS SUBCLASS (ONE SUBCLASS PER BLOCK)								_			-	╁	-		· · · · · · · · ·	
348	552										<u> </u>					·
	1							<u> </u>	<u> </u>		_	_ _	_			
	•		-			<u> </u>		-	<u> </u>				_			
	-					 		-					+	_		
					-	-			 				+		-	
			 			╢			<u> </u>		\dashv					•
		-	1			\vdash				- "		\dashv	+	\dashv		
·····						\vdash						\top	_	\neg		
												1	_	_		
	<u> </u>															
	·					<u> </u>						_ _	\perp	_		
	ļ					<u> </u>		_		•			_ _			
	ļ		-			<u> </u>							-			
 ,			 										-			
	ļ		-					 					-			
	-		-			 		\vdash						-		
	-		 					 					- -			
	·												+			
		l. -				 						_	+	\dashv		
	ļ		 			1							\top			
				·												
			<u> </u>										\perp	_		
													_	\downarrow		
	ļ											_	\bot	_		
	ļ		 _ 			 		_					+	- -		
					4	\leftarrow		£ /	, 	Щ.				"		
Nguyen, My X 09/19/2007 (Assistant Examiner) (Date)		S	Rafael Perez-Gutierrez Supervisory Patent Examiner Technology Center 2600 Art Unit 2617					z niner 00	Total Claims Allowed:							
			li .	erez-Gutier						0.0	O.G. Print Claim(s)				O.G. Print Figure	
(Legal Instruments (Date) Examiner)			(Primary	nary Examiner) (Date)				Date)	12 4 and 6							